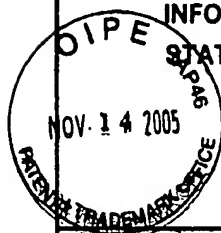
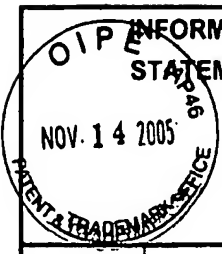


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|--|---------------------|--------------------------|-------------------------|---|--|
| | | | | Filing Date | November 19, 2003 |
| | | | | First Named Inventor | Guillorn |
| | | | | Group Art Unit | 2881 |
| | | | | Examiner Name | Fernandez, Kalimah <i>Nikita Wells</i> |
| Sheet | 1 | of | 1 | Attorney Docket | UBAT1530 |
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| Examiner Signature | <i>Nikita Wells</i> | | | Date Considered | <i>March 13, 2006</i> |



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| Examiner Signature | | <i>Nikita Wells</i> | | Date Considered | <i>March 13, 2006</i> |